

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

Patent Application Serial No. Unknown
 Filing Date Filed Herewith
 Inventor Garo J. Derderian et al.
 Assignee Micron Technology, Inc.
 Group Art Unit Unknown
 Examiner Unknown
 Attorney Docket No. MI22-2444
 Customer No. 021567
 Title Methods of Forming Trench Isolation Regions

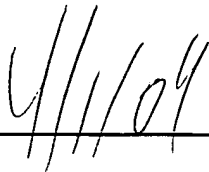
INFORMATION DISCLOSURE STATEMENT

References -- See Attached Form PTO-1449


The attached form PTO-1449 is submitted in compliance with 37 CFR §1.56. Pursuant to 1276 OG 55, August 5, 2003, no copies of cited U.S. patents or U.S. patent application publications are included herewith, as the date of filing of this patent application occurs after June 30, 2003. No admission is made regarding whether all the listed references are prior art.

Respectfully submitted,

Dated:



By:


 David G. Latwesen
 Reg. No. 38,533

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LIST OF ART CITED BY APPLICANT (Use several sheets if necessary)				APPLICANT: Garo J. Derderian et al.			
				FILING DATE Filed Herewith		GROUP Unknown	

U.S. PATENT DOCUMENTS							
*Examiner's Initials		Document Number	Date	Name	Class	Subclass	Filing Date If Appropriate
	AA	5,393,694	02/28/95	Mathews			
	AB	6,261,922 B1	07/17/01	Walker et al.			
	AC	6,323,104 B1	11/27/01	Trivedi			
	AD	6,340,624 B1	01/22/02	Doan et al.			
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	AF	6,391,738 B2	05/21/02	Moore			
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	AH	6,583,028 B2	06/24/03	Doan et al.			
	AI	6,593,206 B2	07/15/03	Dickerson et al.			

FOREIGN PATENT DOCUMENTS								
		Document Number	Date	Country	Class	Subclass	Translation	
							Yes	No
	AJ							
	AK							
	AL							

OTHER REFERENCES (including Author, Title, Date, Pertinent Pages, Etc.)			
	AM		
	AN		
	AO		
EXAMINER		DATE CONSIDERED	

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